

# **ECE201A: Fundamentals of Computer-Aided Design of VLSI Circuits and Systems**

**Puneet Gupta**

Some notes adopted from  
Andrew B. Kahng  
Lei He  
Igor Markov  
Mani Srivastava

# Instructor Info

- Puneet Gupta
  - <http://nanocad.ee.ucla.edu>
  - [puneetg@ucla.edu](mailto:puneetg@ucla.edu)
  - 6730C Boelter Hall
- Office hours
  - On Campus: 3pm-4pm Thursdays
  - MSOL: 5pm-6pm Thursdays on Zoom
- “TA”: George Karfakis

# Syllabus

- RTL (Verilog) to GDSII (layout) flow for large-scale digital designs
  - Logic Synthesis
  - **Physical Design** (partitioning, floorplanning, placement, routing)
  - Test and design for test
- Focus on CAD algorithms
- No textbook. Recommended texts:
  - Assigned paper readings
  - “VLSI Physical Design: From Graph Partitioning to Timing Closure”, Springer
  - “Handbook of Algorithms for Physical Design Automation”, CRC Press
  - “EDA for IC System Design, Verification, and Testing”, CRC Press
  - “EDA for IC Implementation, Circuit Design, and Process Technology”

# Prerequisites

- Familiarity with digital circuit design
  - E.g., EE216A, EE115C, EE116B
- Familiarity with basic algorithms and data structures
  - E.g., CS180, CS32
- Reasonable programming skills in C++
  - We will use OpenAccess C++ API for programming throughout the course
- Familiarity with Linux
- Please attempt the following small quiz on your own. If you get less than 7/10, you should reconsider taking the class.
- [Basic knowledge prerequisite quiz for ECE201A Survey \(surveymonkey.com\)](#)

## Useful Websites

- EETimes, EDN, ...
- DeepChip
- USPTO, Google Patents
- Companies
  - EDA: Synopsys, Cadence, Mentor, ...
  - Foundry: TSMC, UMC, GlobalFoundries, SMIC, ...
  - IP: ARM, Dolphin, CEVA, ...
- DAC, ICCAD, DATE, ASP-DAC, ...
- ITRS ([public.itrs.net](http://public.itrs.net))

# Grading

- 5-6 Programming assignments/labs + 1-2 homeworks: 40%
  - All homeworks to be done individually
- Occasional paper per week of reading assignment
  - Homeworks/Quizzes may contain questions pertaining to reading
- Final Project: 40%: Teams of 2 (or 1)
  - Projects assigned in Week 4.
  - Midterm project report due mid-Week 8 (10%)
  - Final project report due end of Week 10
  - 5% points bonus if you do project by yourself (max is still 40%)
- Two in-class quizzes (done on Gradescope): 20%
- If you are taking the course for S/U grade, do NOT submit the project (i.e., only labs/homeworks + quizzes need to be done)

# Logistics

- We will use Piazza and BruinLearn for the class.
  - Grading will be on Gradescope
- HW/Lab report submissions
  - Put the code, etc in a clearly marked readable directory; email the pointer to the TA.
  - For homeworks we will use online submission on Gradescope
  - Only PDFs acceptable
  - Absolutely no email attachments
- Please make sure to have working SEAS logins
  - You have little disk space for course. Use it carefully.
  - Make sure you can login to [eeapps.seas.ucla.edu](http://eeapps.seas.ucla.edu)
- PTE Policy
  - If you are PhD student, email me for a PTE#
  - If you are M.S. student, make sure you try the quiz; *and* you should have taken ECE216A (or equivalent) and be very comfortable with C++ programming. Only CES M.S. students, please.

# System Implementation Choices

- General Purpose Microprocessors
- Domain-specific processors
  - DSP
  - Network processors
  - Graphics
- FPGA
- Gate Array (structured ASIC)
- ASIC: single purpose chips
  - Full-custom
  - Cell-based

Speed



Power



Cost



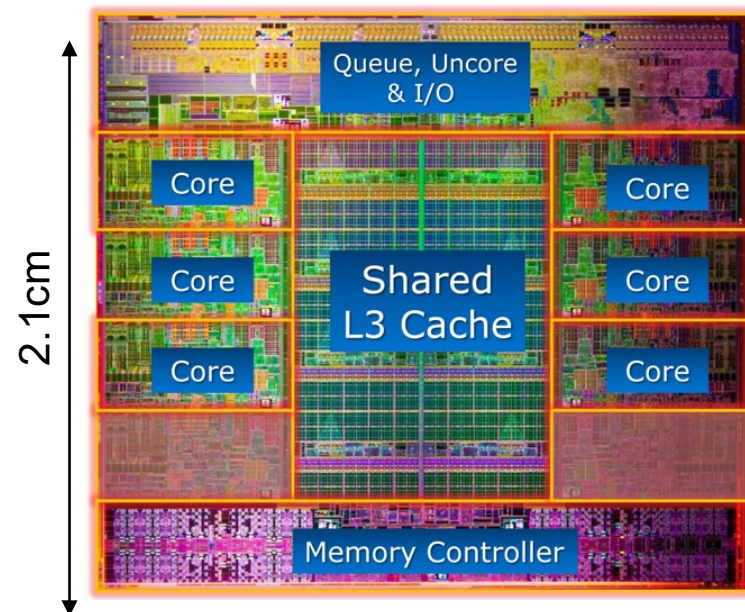
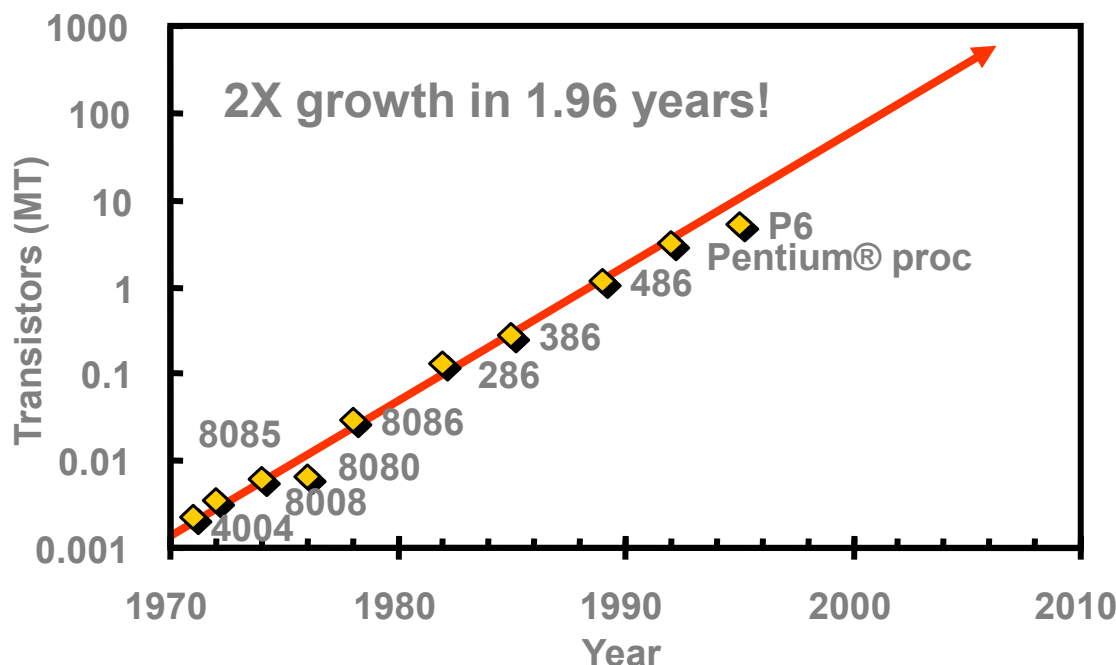
High  
Volume

Low

Volume



# IC Cost and Integration Drivers



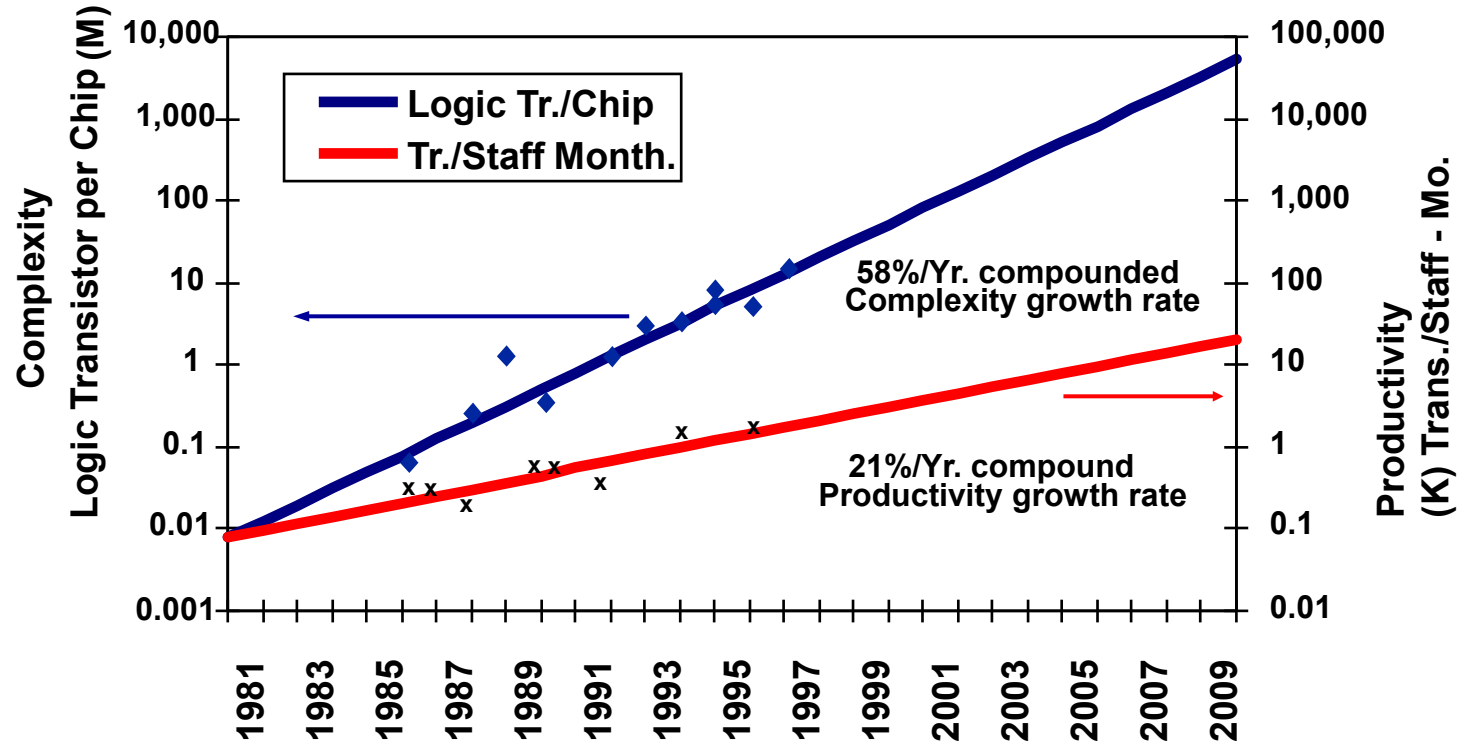
2011 Xeon "Sandy Bridge"  
2.2 Billion Transistors  
32nm technology

- Moore's Law is about *cost*
  - *What is Moore's Law ?*
  - 0.7X dimension (2X area) scaling every technology generation
- Increased integration → decreased cost → more possibilities for semiconductor-based products

- Silicon Complexity = impact of process scaling, new materials, new device/interconnect architectures
  - Non-ideal scaling (leakage, power management, circuit/device innovation, current delivery)
  - Coupled high-frequency devices and interconnects (signal integrity analysis and management)
  - Manufacturing variability
  - Scaling of global interconnect performance (communication, synchronization)
  - Decreased reliability (SEU, NBTI, electromigration, etc)
  - Complexity of manufacturing handoff (reticle enhancement and mask writing/inspection flow, manufacturing NRE cost)

- System Complexity = exponentially increasing transistor counts, with increased diversity (mixed-signal SOC, ...)
  - Reuse (hierarchical design, reuse of verification/test/IP)
  - Verification and test (design for verifiability/test, verification reuse, system-level and software verification, test reuse)
  - Cost-driven design optimization (manufacturing cost modeling and analysis, quality metrics, die-package co-optimization)
  - Embedded software design (platform-based system design methodologies, software verification/analysis, codesign w/HW)
  - Reliable implementation platforms (predictable chip implementation onto multiple fabrics)
  - Design process management (team size / geog distribution, data mgmt, collaborative design)

# The Design Problem: Complexity Outpaces Design Productivity



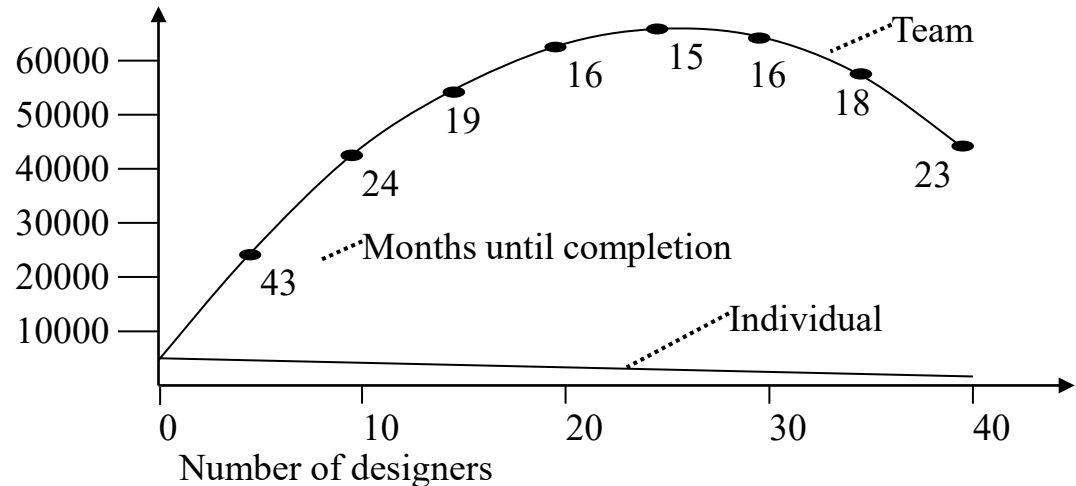
Source: Sematech

**A growing gap between design complexity and design productivity**

# Throwing More Designers Not the Answer: The Mythical Man-month

- In theory, adding designers to team reduces project completion time
- In reality, productivity per designer decreases due to complexities of team management and communication
- In the software community, known as “the mythical man-month”
- At some point, can actually lengthen project completion time! (“Too many cooks”)

- 1M transistors, 1 designer=5000 trans/month
- Each additional designer reduces for 100 trans/month
- So 2 designers produce 4900 trans/month each



[Adapted from *Embedded Systems Design: A Unified Hardware/Software Introduction*. Copyright 2000 Vahid & Givargis]

# Profound Impact on the way VLSI is Designed

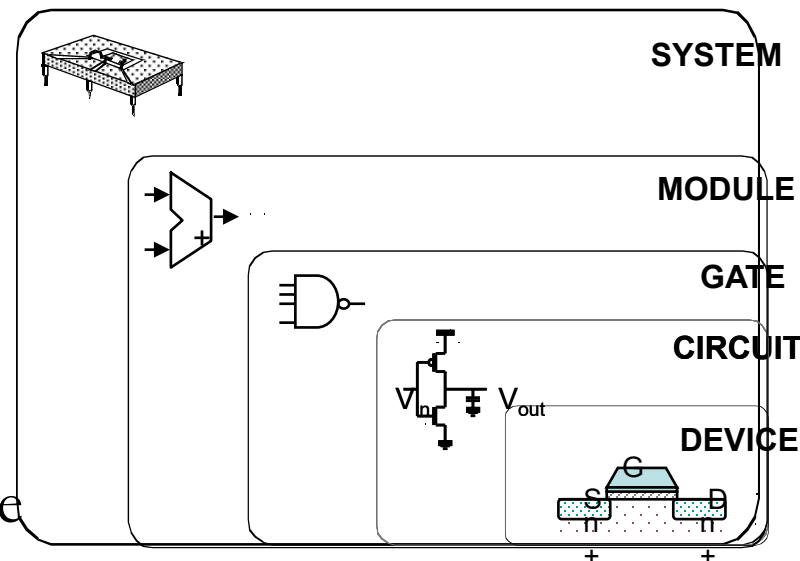


- The old way: manual transistor twiddling
  - expert “layout designers”
  - entire chip hand-crafted
  - okay for small chips... but cannot design billion transistor chips in this fashion
- The (not so) new way: using CAD tools at high level
  - tools do the work...
  - high levels of abstractions
    - synthesis from a description of the behavior
  - libraries of reusable cores, modules, and cells

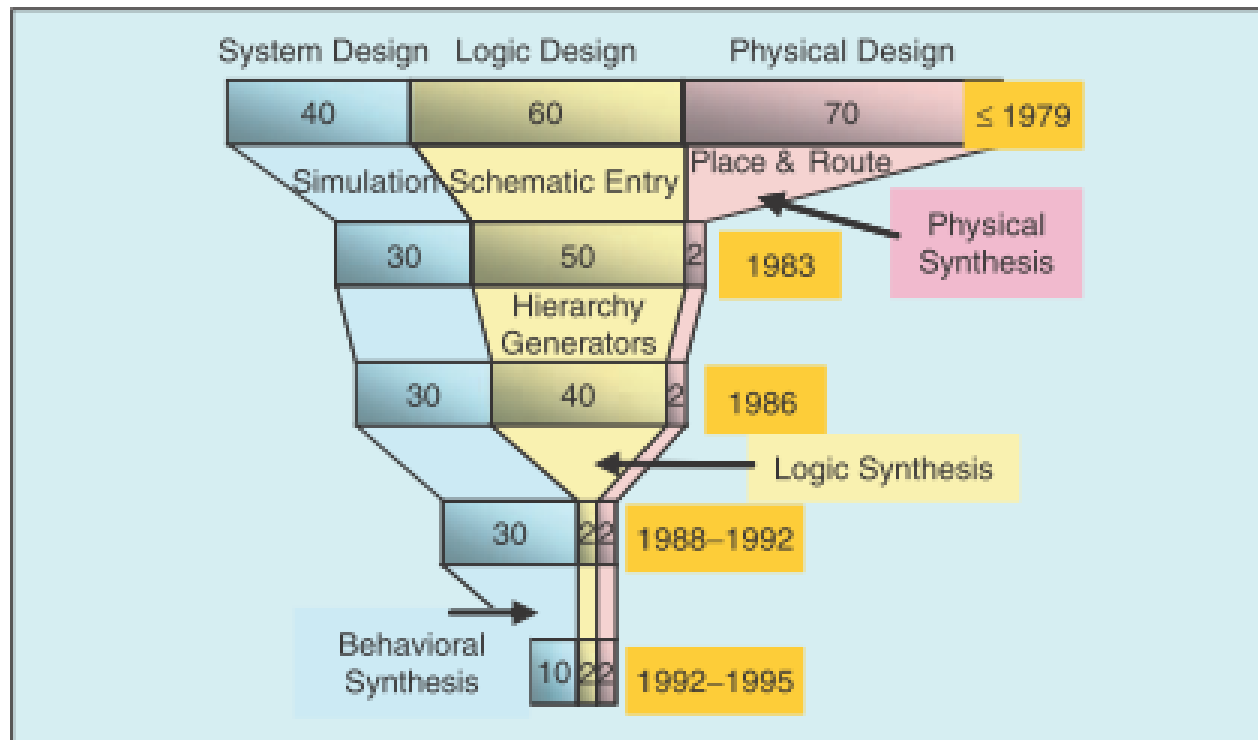
**Chip design increasingly like object-oriented software design!**

# Design Principles

- Partition the problem → divide and conquer, hierarchy
  - Different abstraction levels: RTL, gate-level, transistor-level
- Orthogonalize concerns
  - Logic vs. timing
- Constrain the design space to simplify the design process
  - Balance between design complexity and performance
  - E.g., standard-cell methodology vs. custom design



# History of Progress in EDA

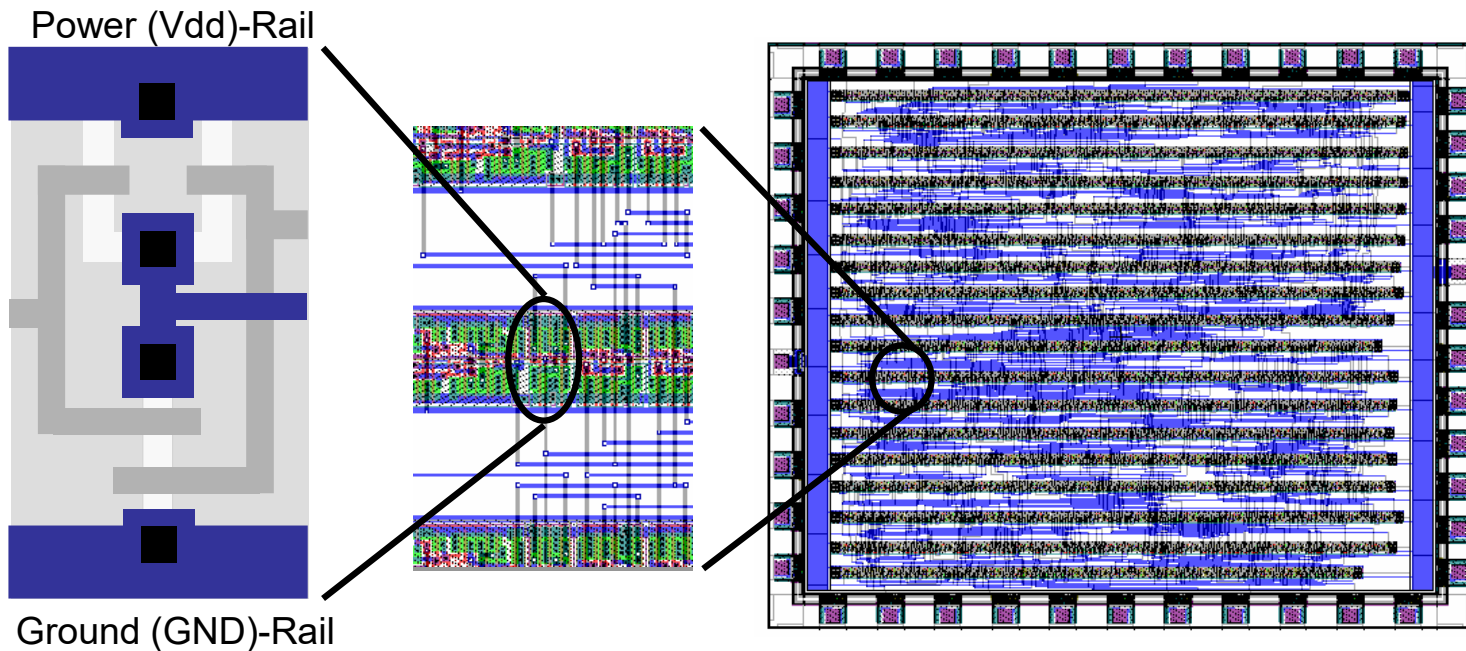
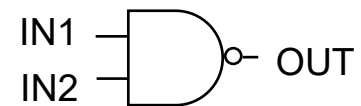
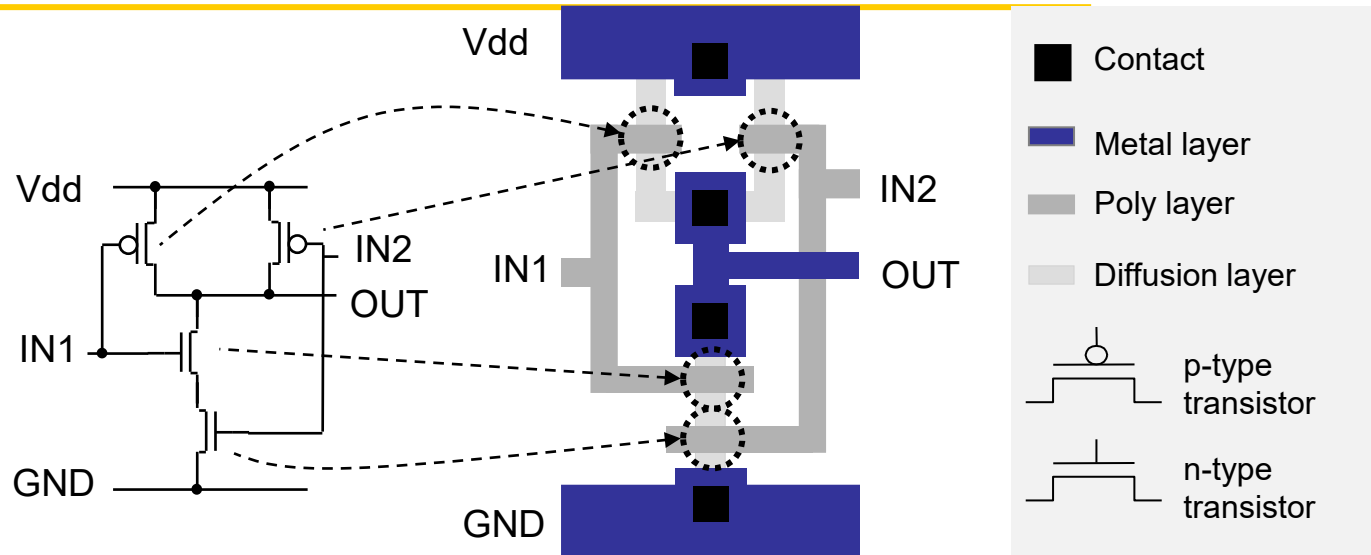


- Reading uploaded on Piazza
  - History of EDA at IBM



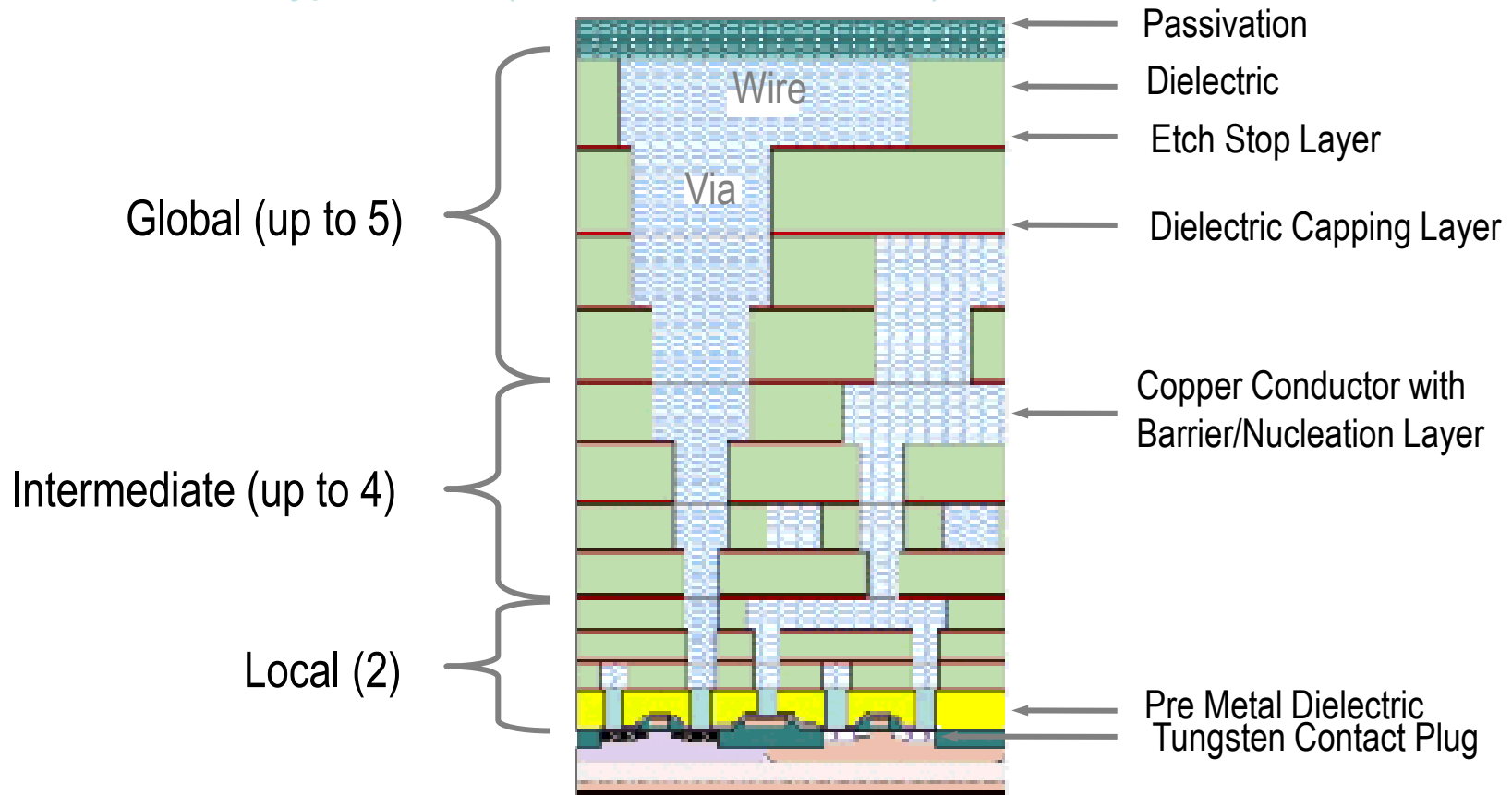
5 min break

# The Layout



# How Is It Connected?

SEMATECH Prototype BEOL ("back end of the line") metal stack, 2000



- *Reverse-scaled* global interconnects
  - Growing interconnect complexity
  - Performance-critical global interconnects

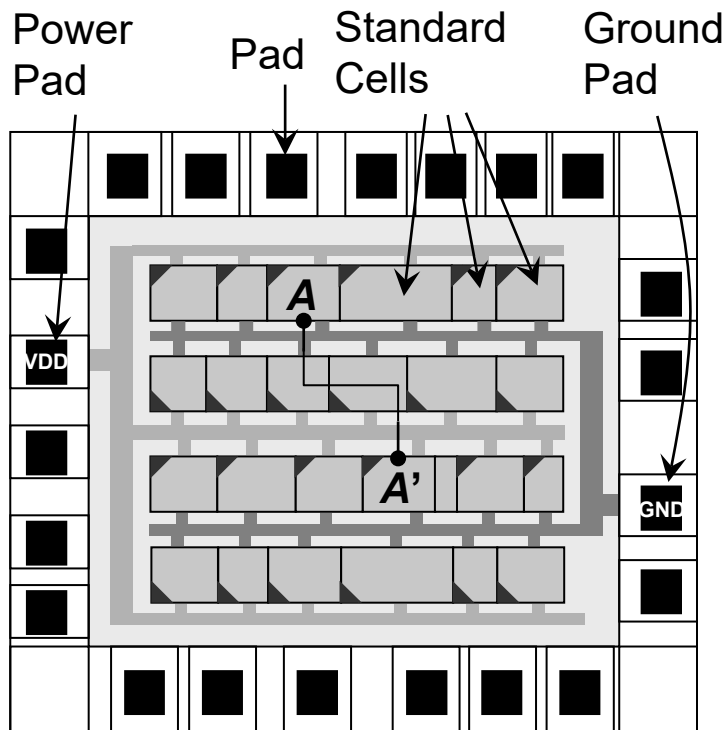
# Comparisons of Design Styles

	full-custom	standard cell	FPGA
cell size	variable	fixed height *	fixed
cell type	variable	variable	programmable
cell placement	variable	in row	fixed
interconnections	variable	variable	programmable

\* uneven height cells are also used

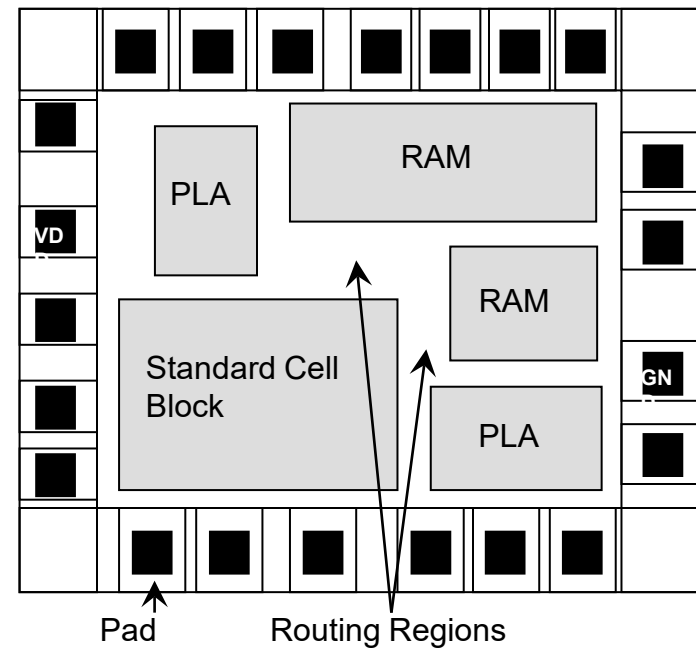
# Standard Cell Layouts

Standard cell layout using over-the-cell (OTC) routing



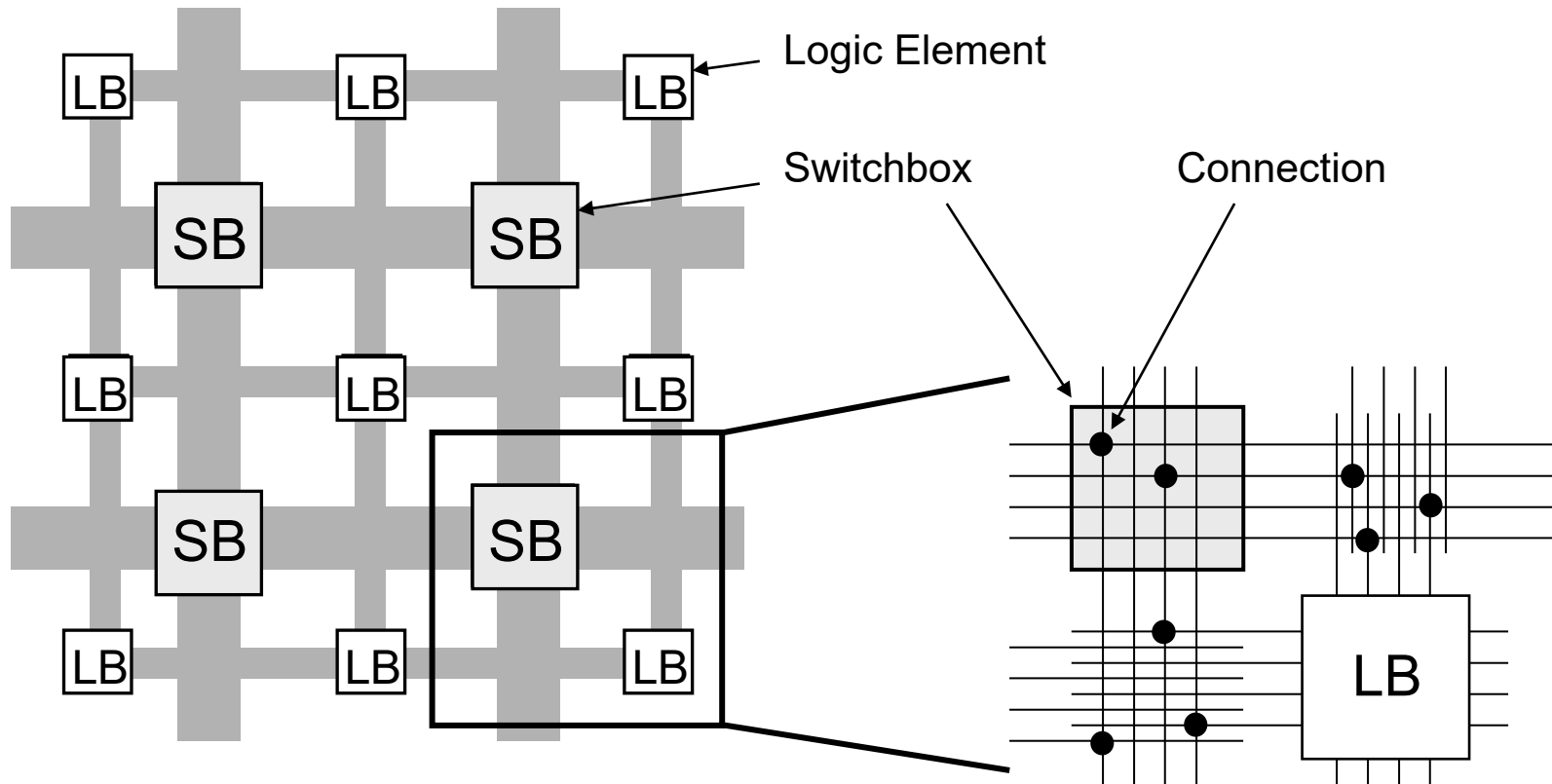
© 2011 Springer Verlag

Layout with macro cells



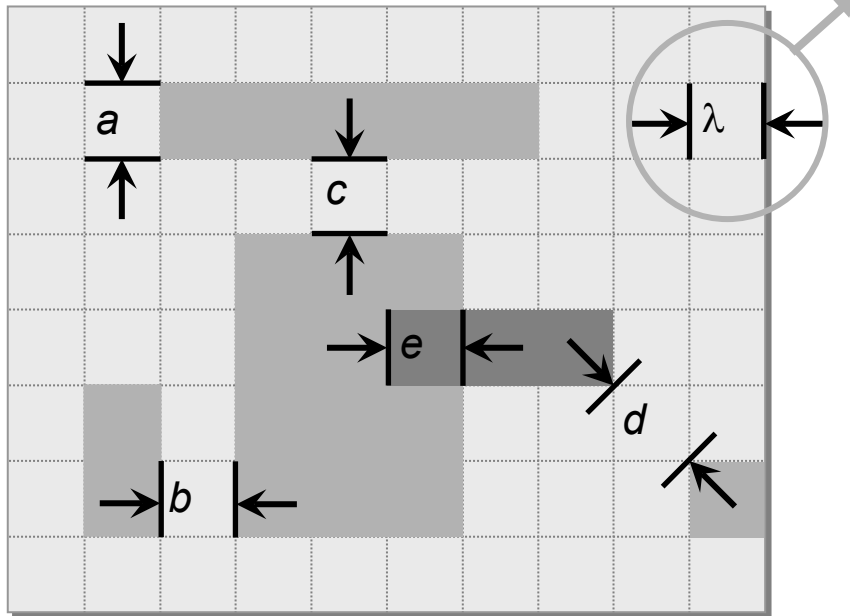
# FPGA Layout

Field-programmable gate array (FPGA)



# Layout Layers and Design Rules

## Categories of design rules



$\lambda$ : smallest meaningful technology-dependent unit of length

Minimum Width:  $a$

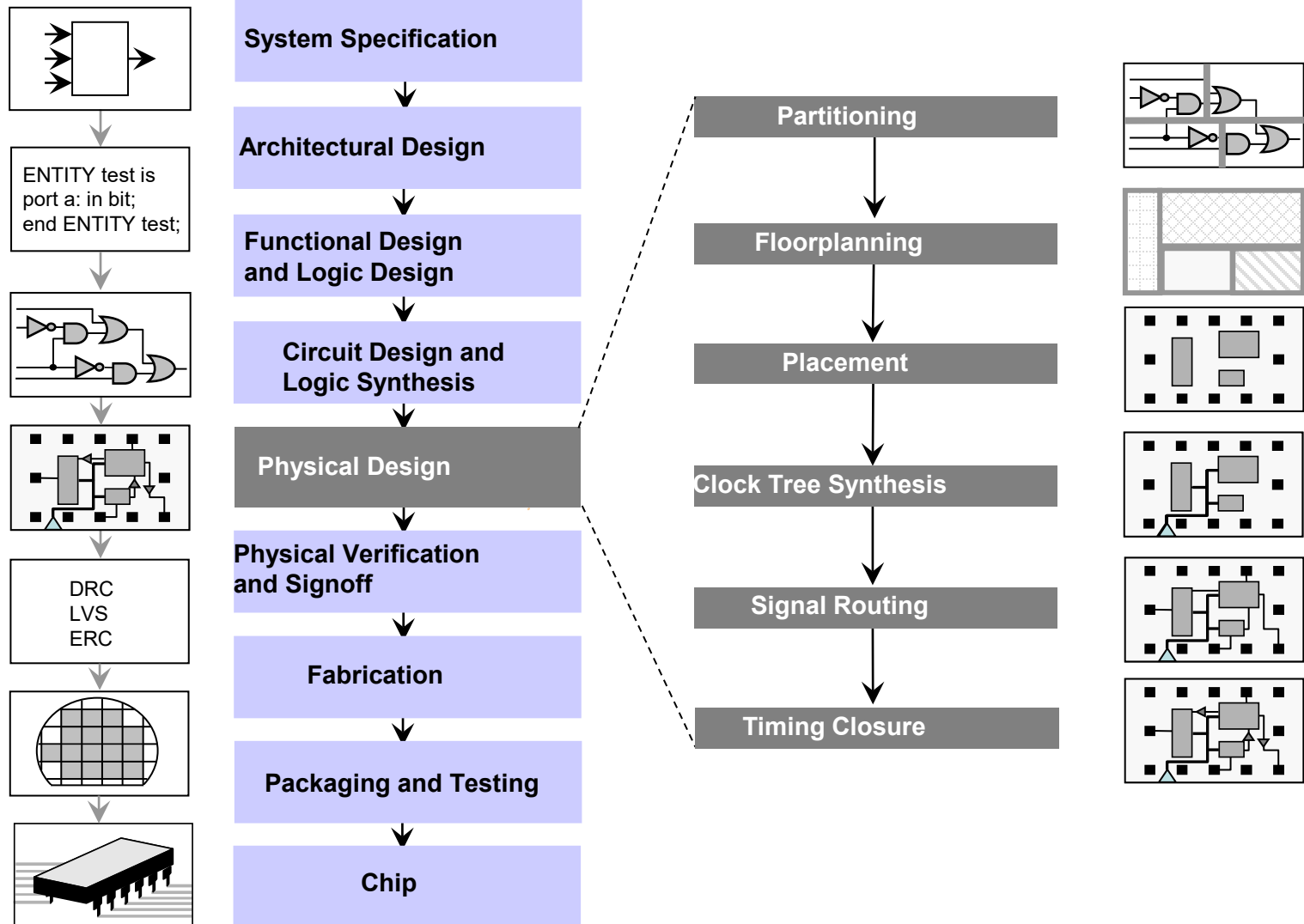
Minimum Spacing:  $b, c, d$

Minimum Overlap:  $e$

- Models and technology data required to execute the design flow
- Power, timing: Liberty, UPF/CPF
- Layout: LEF/DEF, GDSII, OASIS
- Delays and path timing, constraints, parasitics: SDF, SDC, DSPF, SPEF, SPICE
- Layout rules: “DRM” = design rule manual, captured as a “deck” in Calibre, Hercules
- Design data model: OpenAccess, MilkyWay
  - Hierarchy, connectivity, geometry, timing, ...



# VLSI Design Flow



- High-level synthesis (“C to Verilog”)
  - Scheduling
    - Assignment of each operation to a time slot corresponding to a clock cycle or time interval
  - Resource allocation
    - Selection of the types of hardware components and the number for each type to be included in the final implementation
  - Module binding
    - Assignment of operation to the allocated hardware components
  - Controller synthesis
    - Design of control style and clocking scheme
  - Compilation
    - of the input specification language to the internal representation
  - Parallelism extraction
    - usually via data flow analysis techniques
- RTL simulation
  - RTL code, written in Verilog, VHDL or a combination of both, is simulated using testbenches to verify functional correctness
  - Scripted comparison (automated) or Waveform displays (interactive) can be used to verify the outputs

- Logic synthesis: Conversion of RTL to gate-level netlist
  - Targeted to a foundry-specific library
  - Can be performed hierarchically (block by block)
  - Logic minimization done here
  - Timing-driven
    - Clock information (clock is assumed to be ideal zero skew)
    - Primary input arrival times, primary output required times
    - Input driving cells, output loading
    - False paths, multi-cycle paths
    - Interconnect delay may be calculated based on a “wireload model” which uses fanout to estimate delay
- Verification of synthesis results
  - Formal verification
    - RTL description and gate level netlist are compared to verify functional equivalence, thereby verifying the synthesis results
  - Gate-level simulation
    - Covers both functionality and timing
    - Correctness is only as good as the test vectors used
    - Delays are backannotated from the synthesis run

- Physical Floorplanning: Defines the basic chip layout architecture
  - Define the standard cell rows and I/O placement locations
  - Place memories and other macros
  - Define power distribution structures such as rings and stripes
  - Allow space for power, clock, major buses
- Place & Route
  - Automatically place the standard cells
  - Generate clock trees
  - Add any remaining power bus connections
  - Route clock lines
  - Route signal interconnects
  - Design rule checks on the routes and cell placements
  - Timing driven tools
    - Require timing constraints and analysis algorithms similar to those used during the static timing analysis step

- Static Timing Analysis
  - Verifies that design operates at desired frequency in an input-independent pessimistic fashion
  - Used throughout synthesis, placement, routing
- RC(L) Extraction
  - Calculate resistance and capacitance (and inductance) of interconnects
    - Based on placement of cells
    - Routing segments
  - Drive delay calculation, signal integrity analysis (crosstalk, other noise), static timing
- Physical Verification
  - DRC – Design Rule Check
    - Polygon/Layer spacing rules
    - Verifies the design rules (DRC)
  - LVS – Layout Versus Schematic
    - Verifies that layout and netlist are equivalent at the transistor level
- Functional Verification
  - LEQ – Logical Equivalence Check
    - Check whether two netlists are logically the same
  - Simulation, emulation, ....

# Release to Manufacturing



- Final edits to the layout are made and final design rules and other manufacturing constraints are checked
- Manufacturing information such as scribe lanes, seal rings, mask shop data, part numbers, logos and pin 1 identification information for assembly are also added
- ‘Tapeout’ documentation is prepared prior to release of the GDSII to the foundry
  - GDSII (Stream Format)
    - Final merge of layout, routing and placement data for mask production
- Pad location information is prepared, typically in a spreadsheet
- Manufacturing steps
  - generation of masks
  - silicon processing
  - wafer testing
  - assembly and packaging
  - manufacturing test

# Logistics

- Week 1 paper reading (uploaded to Piazza):
  - “EDA in IBM: Past, Present, and Future”
- Next lecture: quick overview of common algorithms and terminology in CAD